



# RAM Mounts Testing Summary

## RAM® EZ-Roll'r™ Dock Samsung Tab Active5 & 3

### Products Covered

RAM-101-225B-SAM60P-V7B1U  
RAM-101B-225B-SAM60PD-AU-V7B1U  
RAM-B-101-225B-SAM60P-HARU  
RAM-B-101-225B-SAM60P-V7B1U  
RAM-B-101-225B2-SAM60P-V7B1U  
RAM-B-189-18-SAM60-CIGU  
RAM-HOL-SAM60-A-111B-MTD-V7B1U  
RAM-HOL-SAM60-A-111B-MTDU  
RAM-HOL-SAM60CP-AU  
RAM-HOL-SAM60CP-CAU  
RAM-HOL-SAM60CP-CU  
RAM-HOL-SAM60CP-RJ45AU  
RAM-HOL-SAM60CP-V7CU  
RAM-HOL-SAM60CPU  
RAM-HOL-SAM60P-CIGU  
RAM-HOL-SAM60P-HAR-POLINDU  
RAM-HOL-SAM60P-HARU  
RAM-HOL-SAM60P-MICROBMU  
RAM-HOL-SAM60P-NCU  
RAM-HOL-SAM60P-POLINDU-V7B1U  
RAM-HOL-SAM60P-PS-NCU  
RAM-HOL-SAM60P-PS1U  
RAM-HOL-SAM60P-PSU  
RAM-HOL-SAM60P-TRI1U  
RAM-HOL-SAM60P-V7B1U  
RAM-HOL-SAM60P-WM1U  
RAM-HOL-SAM60PD-AUDU  
RAM-HOL-SAM60PD-MICROBMU  
RAM-HOL-SAM60PD-NCU  
RAM-HOL-SAM60PD-TRIS-NCU  
RAM-HOL-SAM60PD-TRI1U  
RAM-HOL-SAM60PD-V7-ZON1U  
RAM-HOL-SAM60PD-V7B1U  
RAM-HOL-SAM60PD2U  
RAM-HOL-SAM60PDU  
RAM-HOL-SAM60PU

### Accompanying Power Supplies

RAM-GDS-CHARGE-MUSB-V7B1U





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Test	Description
<b>Vibration – operational</b>	MIL-STD-810H, Method 514.8, Table 514.8C-VII, Category 4. Tested performed with unlocked dock and device oriented vertical, transverse, and longitudinal. 1 hour each axis, 3 hours total.
<b>Functional Shock - operational</b>	MIL-STD-810H, Method 516.8, Procedure 1, 3 positive and 3 negative pulses per vertical, longitudinal, and transverse axis. 18 total pulses. Pulses are 20G, 11ms terminal peak sawtooth.
<b>Pogo Pins – Cycle rating</b>	Pogo pins rated to 100k cycles
<b>USB Validation Protocol, Speed, Power</b>	NPI Developed Testing Specification for USB 2.0 Compliance up to 480Mbps, 4.75-5.25VDC @ 900mA per port
<b>Power Supply Input Voltage Tolerance</b>	NPI Developed Testing Specification for Cycle Testing of Input Voltage and variable current
<b>Power Supply Output Voltage Tolerance</b>	NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current
<b>Power Supply Load Test</b>	NPI Developed Testing Specification for Cycle Testing of Output Voltage and variable current
<b>Regulatory Compliance</b>	FCC, IC CE, RoHS, WEEE
<b>Safety, Emission, Immunity (Ram Power Supply)</b>	CE EN:55032, EN 55035, IEC 61000-6-1, EN 62368-1, e-Mark